

INFN interests for ePIC SVT

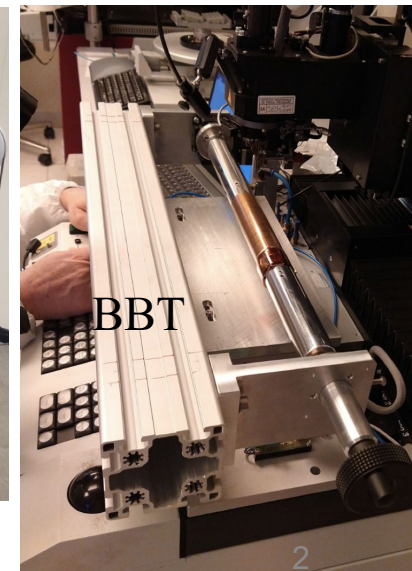
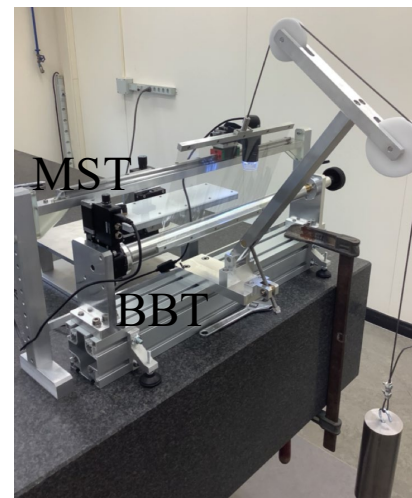
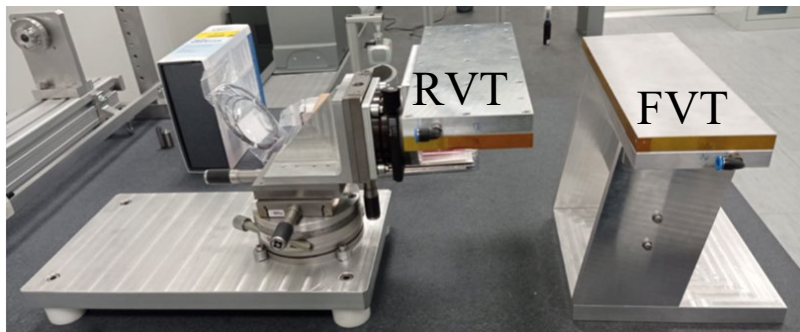
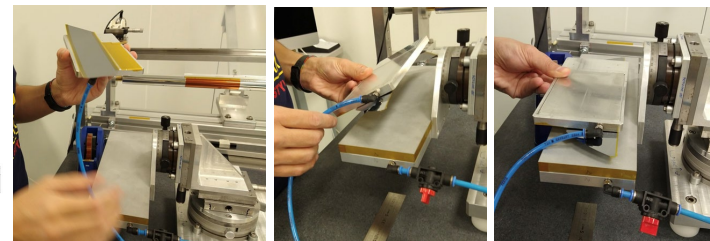
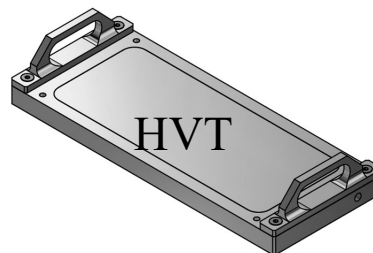
- **Participating groups (contacts):** Bari (D. Elia), Trieste (G. Contin), Padova (R. Turrisi)
- **Ongoing activities for ALICE ITS3:**
 - ✓ Bari: bending and interconnection studies, development of super-ALPIDE prototypes, test of APTS OP-AMP
 - ✓ Trieste: bending, test and characterization of flat and bent DPTS, preparation of bent APTS SF samples
 - ✓ Padova: test and characterization of APTS SF, setup for testing DPTS in preparation
 - ❖ Bari and Trieste coordinating the ITS3 - WP4 “Bending, thinning and interconnections” (D. Colella, G. Contin)
 - ❖ Trieste coordinated the DPTS characterization campaign within ITS3 so far
- **Current involvement/activities in EICSC and tracking WG:**
 - ✓ eRD111 (since FY22): *Forming modules from stitched sensors* → 30 k\$ for FY23
 - ✓ eRD113: *Progress in testing and characterization* → 30 k\$ for FY23
 - ✓ gen. R&D: *Additive manufacturing of power&data redistribution layers on thin large-area silicon* → 49 k\$ for FY23
 - ✓ simulation studies with Fun4All/DD4HEP vs fast simulation, development of Root-based event display (S. Kumar)

Activity for vertex layers

Silicon bending procedure and tooling

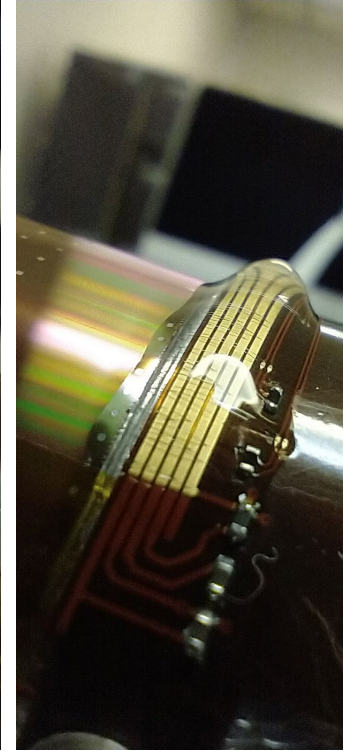
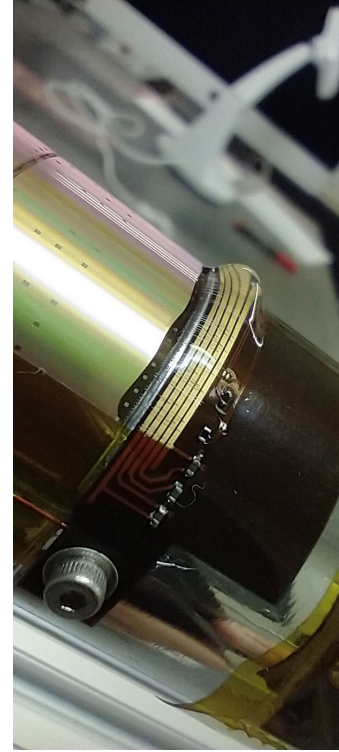
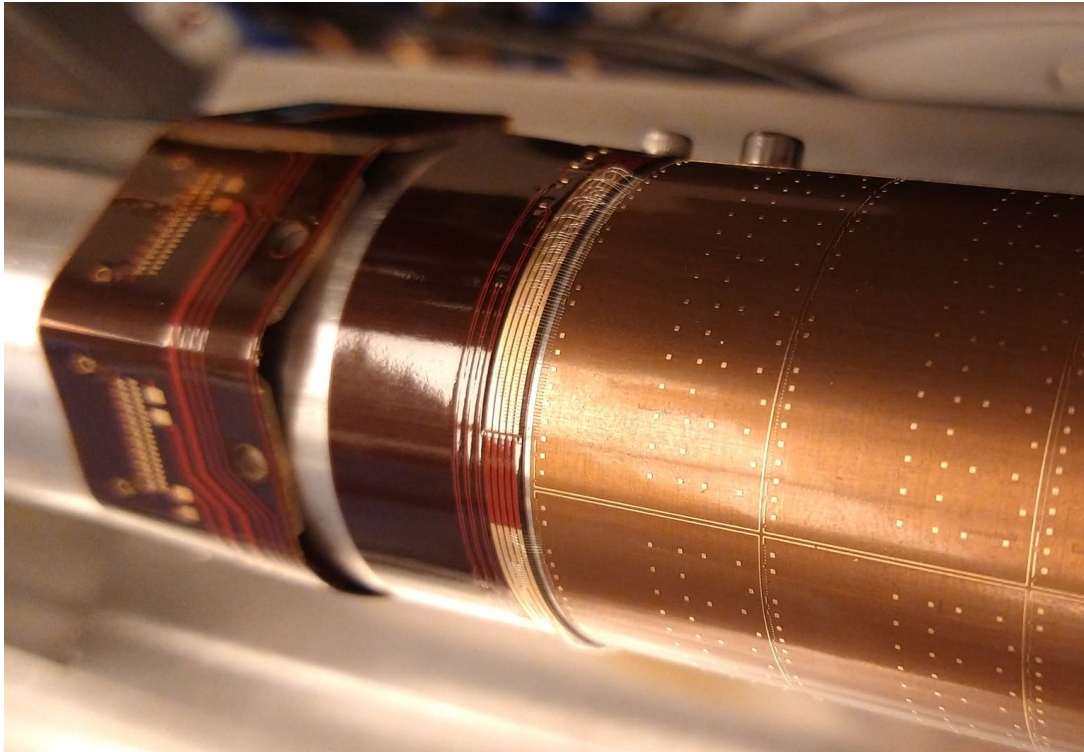
LIST OF TOOLS

- 1.Fixed vacuum tool (FVT)
- 2.Rotating vacuum tool (RVT)
- 3.Handling vacuum tool (HVT)
- 4.Microscope tool (MST)
- 5.Bending Bonding tool (BBT)



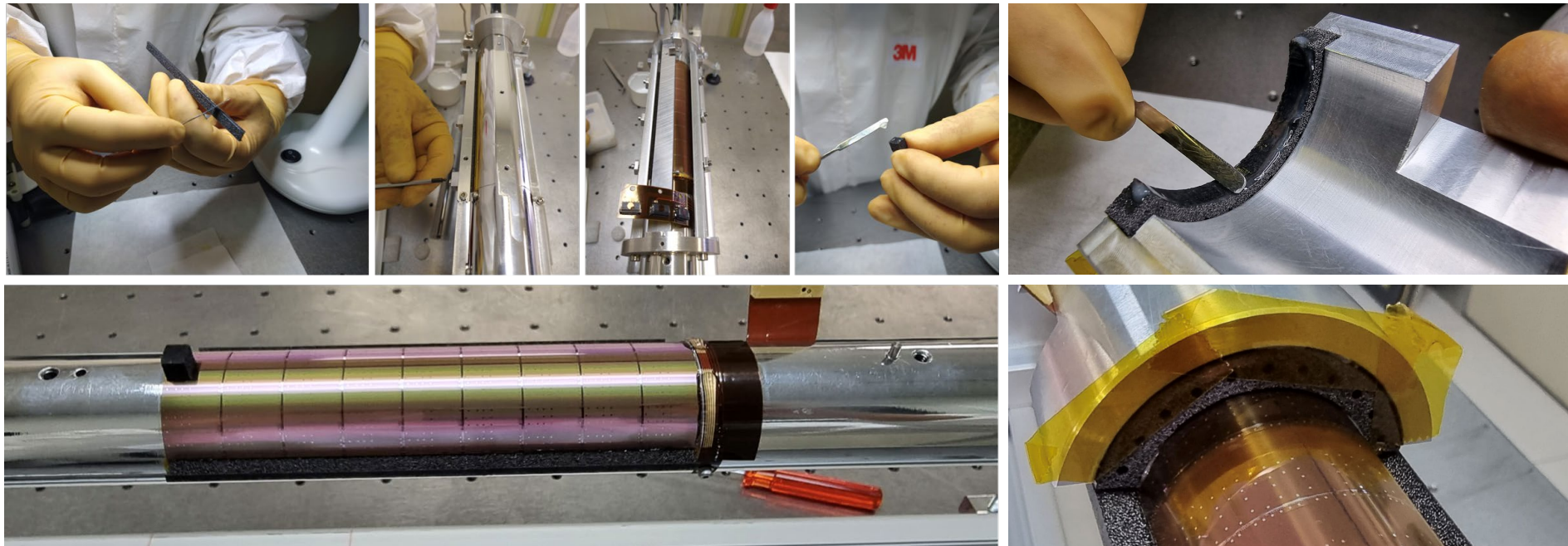
Activity for vertex layers

Silicon interconnection to flex



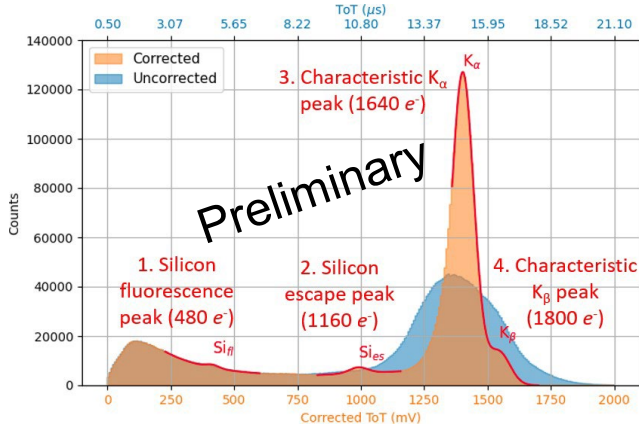
Activity for vertex layers

Support structures gluing to the sensor

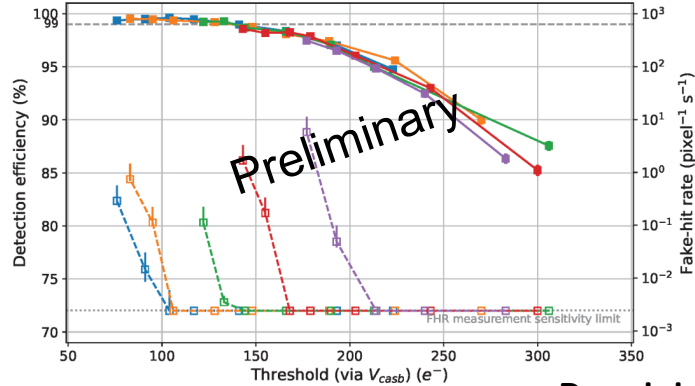


Bending and testing 65 nm CMOS chips

- Response to Fe55

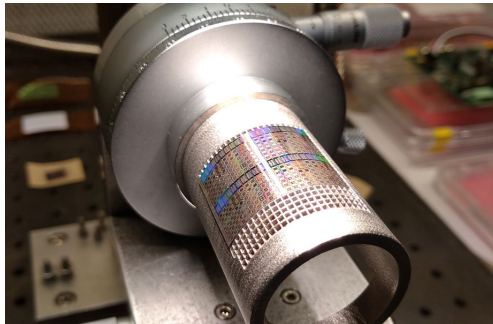


- Efficiency measurement with MIPs

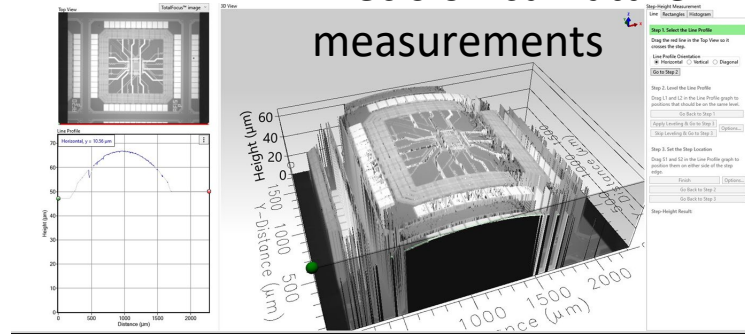


DPTS paper pre-print:
<https://arxiv.org/abs/2212.08621>

- Reticle Bending



- Precision curvature measurements



Planned contributions to the ePIC SVT

- Funding and labor force
 - ✓ Project not officially funded yet, ~1M\$ in-kind contribution to SVT is foreseen for construction phase
 - ✓ Scientific staff ramping up to 3-5 FTE during R&D phase + technical personnel. Expected to grow for construction, to be defined
- R&D for vertex layers
 - ✓ **Bending and interconnections** based on bending/interconnection/prototyping activities for ITS3
 - ✓ General contribution on **sensor test and characterization** (also connected to the eRD111 targets for this year)
 - ✓ Contribution to **FPC development and testing**
 - ➔ overall effort **to be better defined** based on effective dedicated labor force growing in the groups
- Construction of vertex layers
 - ✓ Possible **in-kind** contribution to **silicon production runs, thinning and dicing**
 - ✓ Considering specific construction items compatible with ongoing R&D and available labor force, for example:
 - ✓ On-wafer large-area **sensor probe testing**
 - ✓ **FPC** production and integration
 - ✓ Participation in **chip bending and layer integration**
 - **To be decided** based on the other groups' interests and the available resources